

Application/Control No.	Applicant(s)/Patent under Reexamination
10/521,481	KRENGEL ET AL.
Examiner	Art Unit
David E. Bochna	3679

SEARCHED						
Class	Subclass	Date	Examiner			
285	406	11/9/2007	DB			
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INTERFERENCE SEARCHED					
Class	Subclass	Date Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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